

Lubrication approximation-based model and computations of pulsed laser induced dewetting in thin metallic films

Mikhail Khenner¹, Ramki Kalyanaraman^{2,3}, Sagar Yadavali²

¹Department of Math and Computer Science, Western Kentucky University

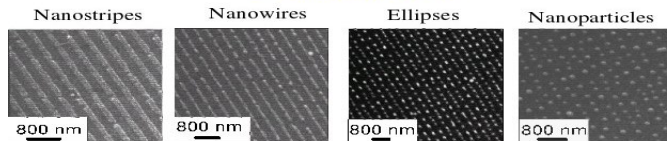
²Department of Chemical and Biomolecular Engineering, Department of Materials Science and Engineering, University of Tennessee at Knoxville

³Sustainable Energy Education Research Center, University of Tennessee at Knoxville

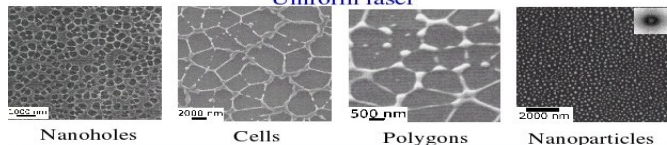
48th Annual Technical Conference of Society of Engineering Sciences, Northwestern University, October 12, 2011

Single-layer films: Nanoscale arrays

2-beam interference



Uniform laser



Increasing # of laser pulses n →

Selected publications by Kalyanaraman group (experiment & theory):

C. Favazza et al., J. Appl. Phys. 102, 104308 (2007)

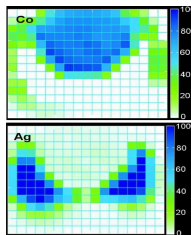
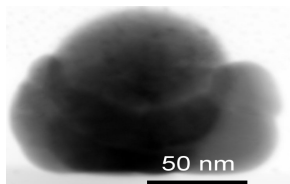
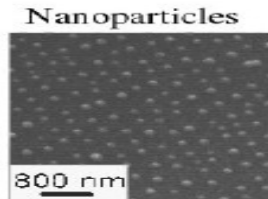
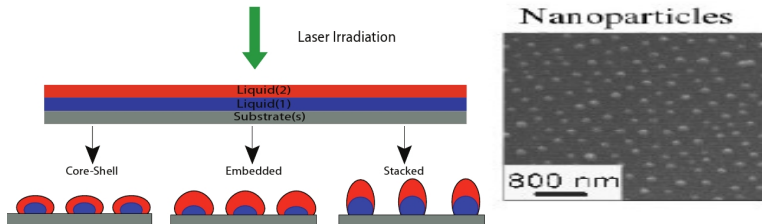
J. Trice et al., Phys. Rev. Lett. 101, 017802 (2008)

L. Longstreth-Spoor et al., J. Phys. D: Appl. Phys. 39, 5149 (2006)

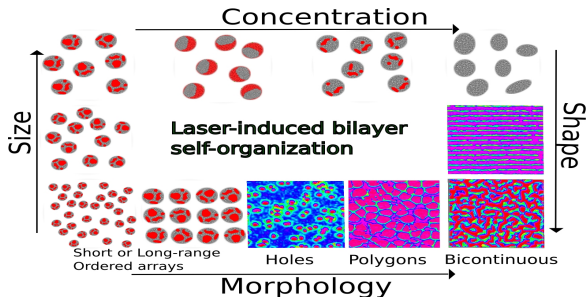
C. Favazza et al., Appl. Phys. Lett. 91, 043105 (2007)

J. Trice et al., Phys. Rev. B 75, 235439 (2007)

Nanoparticle morphologies from bilayer dewetting



Vision of a multifunctional nanostructured surface platform based on multi-layer films



Pulsed laser self-organization of multilayer films made from immiscible metals, like Co and Ag, can be used to synthesize a matrix of discrete micro-regions with varying nanoscale morphology, size, shape, and composition. *Thus a platform with unique multifunctional behavior for sensing and detection can be made.*

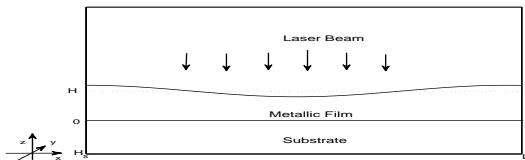
Modeling the complete dewetting cycle from a continuous film to a nanoparticles state

Treat thin film ($h \sim 10nm$) as liquid at all times, and model dewetting as continuous in time

Justification:

- Film is melted “instantaneously” when a pulse hits - energy flux $\sim 10^{11} \text{ J/sm}^2$;
- Film dewets while the pulse lasts (10 ns);
- Film solidifies “instantaneously” after the pulse is gone - due to large heat loss to a substrate, freezing the morphology;
- Next pulse quenches in the morphology and the cycle repeats (50 cycles/second).

A model for single layer films



Major physical factors contributing to particles self-organization through film dewetting:

- Unusual, thickness-dependent heat transfer in the film - due to nonlinear optical absorption of light and nonlinear reflectivity
- Thermocapillary (Marangoni) fluid flow arising due to the surface tension dependence on temperature
- Long-range intermolecular (van der Waals) forces between the substrate and film surface molecules
- Capillary fluid flow (minimization of the surface area at given fluid volume by the surface tension)

Lubrication approximation: leading-order expansion in $\epsilon = H/L \ll 1$

- Momentum (Stokes) and continuity equations

$$\nabla \cdot \boldsymbol{\Omega} = 0, \quad \nabla \cdot \mathbf{u} = 0$$

- Energy equation

$$\frac{\kappa}{\rho c_p} \nabla^2 T + Q = 0,$$

where

$$\boldsymbol{\Omega} = -P\delta_{ij} + \eta \left(\frac{\partial u_i}{\partial x_j} + \frac{\partial u_j}{\partial x_i} \right) : \text{stress tensor}$$

$$Q = \frac{\delta J(1 - R(h))}{2} f(x, y, t) \exp(\delta(z - h)) \quad (\text{Beer-Lambert law})$$

$$(0 \leq R(h) = r_0(1 - \exp(-a_r h)) < 1 : \text{nonlinear reflectivity})$$

Remark 1: Interference in the plane of the film enters through

$f(x, y, t)$.

Boundary conditions (I)

At the free surface:

(i) The normal and shear stress balances;

$$\mathbf{n} \cdot \boldsymbol{\Omega} \cdot \mathbf{n} = -\sigma \nabla \cdot \mathbf{n} + \frac{A}{6\pi} h^{-3}, \quad \mathbf{t} \cdot \boldsymbol{\Omega} \cdot \mathbf{n} = \mathbf{t} \cdot \nabla \sigma$$

(ii) The kinematic condition:

$u_3 = h_t + u_1 h_x + u_2 h_y$ ← **this condition is used to derive the evolution PDE for h after u_1 and u_2 have been averaged in the z -direction**

(iii) Newton's law of cooling:

$$\kappa T_z = -\alpha_h (T - T_a)$$

Boundary conditions (II)

At the film-substrate interface $z = 0$:

- No-slip: $u_1 = u_2 = 0$
- No-penetration: $u_3 = 0$
- Continuity of temperature and thermal flux:

$$T = \theta, \quad \kappa T_z = \kappa_s \theta_z$$

θ is the temperature field in the transparent substrate
($R = 0$ for $-H_s \leq z \leq 0$):

$$\frac{\kappa_s}{\rho_s c_{ps}} \nabla^2 \theta + Q = 0$$

$$z = -H_s : \quad \theta = T_s \quad (\text{value from experiment})$$

Dimensionless 1D evolution equation for the film height $h(x, t)$

$$\begin{aligned} h_t = & \frac{\partial}{\partial x} \left[-(C/3)h^3 h_{xxx} + (G/3)h^3 h_x - Ah^{-1}h_x \right. \\ & + M\beta(T_a - T_s)h^2 h_x \\ & + \left\{ -MF_h(1 - R(h)) + MR'(h)F - M\beta(h + \Psi)R'(h)F \right. \\ & \left. \left. + M\beta(1 - R(h))(F + (h + \Psi)F_h) \right\} f(x, y, t)h^2 h_x \right] \end{aligned}$$

Lines 3 and 4: unconventional terms due to laser heating

C : capillary number, G : gravity number, β : Biot number, M : Marangoni number, T_a : ambient temperature, T_s : substrate temperature, A : Hamaker constant, $D = \delta H$: optical thickness, $\Psi = H_s/H\Gamma$, where $\Gamma = \kappa/\kappa_s$

$$\begin{aligned} R(h) &= r_0 (1 - \exp(-a_r h)), \\ F(h, D, \Psi) &= (-\Psi + \exp(-Dh)(\Psi - 1/D) - h + 1/D)/2 \end{aligned}$$

Linear stability analysis for uniform irradiation ($f = 1$)

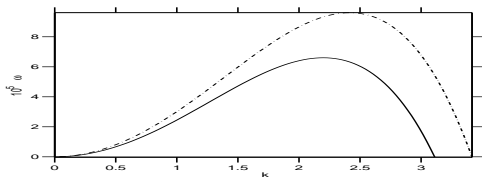


Figure: Variation of ω with k : Dash-dot curve: heat source is zero; solid curve: heat source is non-zero.

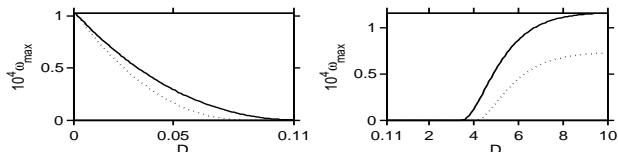


Figure: Variation of ω_{max} with D . Dot curve: $R(h) = 0$; solid curve: $R(h) \neq 0$.

The uniformly heated film is completely stable against small perturbations in some interval of the optical thickness parameter

Computation of a nonlinear evolution of the film (I)

Single laser beam ($f = 1$)

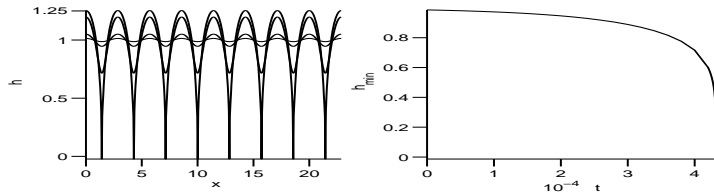


Figure: Profile of the film height (left), and the evolution of the minimum point on the film surface (right). Note the formation of a **nanowire array**. Spacing equals $2\pi/k_{max} \equiv$ wavelength of the fastest growing perturbation ($\omega = \omega_{max}$).

Rupture time $T_r \approx 0.9$ ms (depends on the amplitude of the initial film height).

Computation of a nonlinear evolution of the film (II)

Two-beam interference: $f \equiv f(x) = 1 + 0.99 \cos(0.157(x - \frac{\pi}{2.2}))$

Note: $2\pi/0.157 = 40$: the distance between interference fringes

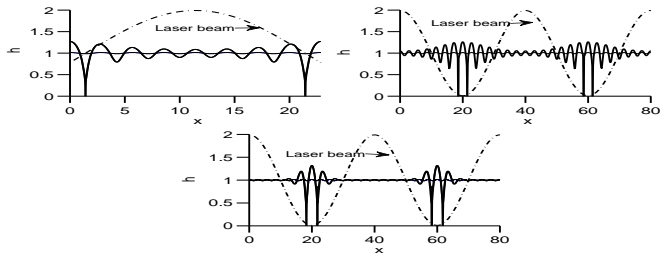


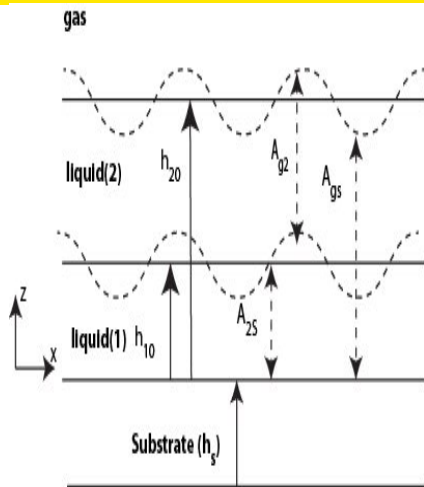
Figure: Top row, left: $H = 10$ nm, 8 wavelengths; Top row, right: $H = 10$ nm, 28 wavelengths; Bottom row: $H = 15$ nm, 28 wavelengths.

The spatial periodicity of nanowires follows the interference imprint.

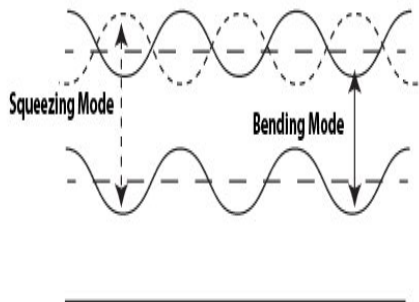
Publication: A. Atena and M. Khenner, Phys. Rev. B 80, 075402 (2009)

A model for 1D bilayer films

Problem Geometry: bilayer + transparent SiO_2 substrate + reflective support layer

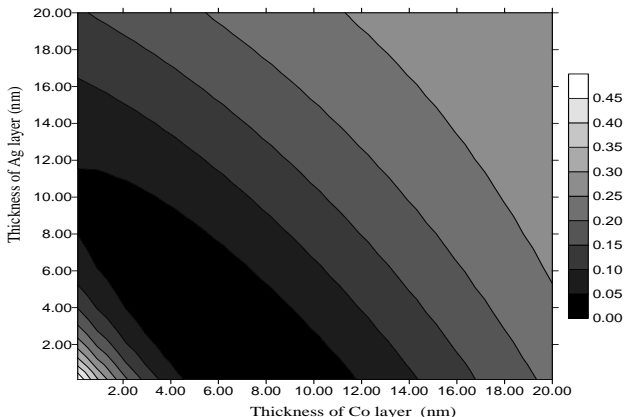


(a)



(b)

Reflectivity (shown: AgCo bilayer, model)



$R = R(h_1, h_2 - h_1)$ is a smooth convex function of its arguments; model adapted from J.S.C. Prentice, "Coherent, partially coherent and incoherent light absorption in thin-film multilayer structures," J. Phys. D: Appl. Phys. **33**, 3139 (2000).

Evolution equations for layers thicknesses (Pototsky et al. (2005))

$$\begin{aligned}\partial_t h_1 &= -\partial_x [F_{11} \partial_x P_1 + F_{12} \partial_x P_2 + \Phi_{11} \partial_x \sigma_1 + \Phi_{12} \partial_x \sigma_2], \\ \partial_t h_2 &= -\partial_x [F_{21} \partial_x P_1 + F_{22} \partial_x P_2 + \Phi_{21} \partial_x \sigma_1 + \Phi_{22} \partial_x \sigma_2]\end{aligned}$$

Here $F_{\ell m}(h_1, h_2 - h_1)$ and $\Phi_{\ell m}(h_1, h_2 - h_1)$ are certain polynomials of a degree at most three

Pressures:

$$\begin{aligned}P_1 &= -\sigma_1 \partial_{xx} h_1 - \sigma_2 \partial_{xx} h_2 + \Pi_1 + \Pi_2 + \rho_1 g h_1 + \rho_2 g (h_2 - h_1), \\ P_2 &= -\sigma_2 \partial_{xx} h_2 + \Pi_2 + \rho_2 g h_2\end{aligned}$$

Disjoining pressures:

$$\begin{aligned}\Pi_1(h_1, h_2 - h_1) &= \frac{A_{s2}}{h_1^3} - \frac{A_{g2}}{(h_2 - h_1)^3} + \frac{S_1 \exp\left(-\frac{h_1}{\ell_1}\right)}{l_1} - \frac{S_2 \exp\left(-\frac{(h_2 - h_1)}{\ell_2}\right)}{l_2}, \\ \Pi_2(h_1, h_2 - h_1) &= \frac{A_{g2}}{(h_2 - h_1)^3} + \frac{A_{sg}}{h_2^3} + \frac{S_2 \exp\left(-\frac{(h_2 - h_1)}{\ell_2}\right)}{l_2}\end{aligned}$$

Surface tensions, heat equations and surface tensions gradients

Surface tensions:

$$\sigma_1 = \sigma_1^{(m)} - \gamma_1 \left(T_1(z = h_1) - T_1^{(m)} \right), \quad \gamma_1 > 0, \quad T_1(z = h_1) > T_1^{(m)},$$

$$\sigma_2 = \sigma_2^{(m)} - \gamma_2 \left(T_2(z = h_2) - T_2^{(m)} \right), \quad \gamma_2 > 0, \quad T_2(z = h_2) > T_2^{(m)}$$

Heat equations are ODEs in z for $T_{1,2} = T_{1,2}(z, h_{1,2}(x))$:

$$\frac{\kappa_{1,2}}{\rho_{1,2} C_{eff}} \partial_{zz} T_{1,2} + \frac{\delta_2 J}{\rho_{1,2} C_{eff}} (1 - R) \exp(\delta_{1,2}(z - h_2)) = 0,$$

$$\frac{\kappa_s}{\rho_s C_{eff}} \partial_{zz} T_s = 0$$

Add physical boundary conditions on the three interfaces: liquid/gas, liquid/liquid and liquid/substrate and solve in CAS

$$\rightarrow T_{1,2} = T_{1,2}(z, h_{1,2}(x))$$

Surface tensions gradients:

$$\partial_x \sigma_1 = -\gamma_1 \left((\partial_{h_1} T_1)|_{z=h_1} \partial_x h_1 + (\partial_{h_2} T_1)|_{z=h_1} \partial_x h_2 \right),$$

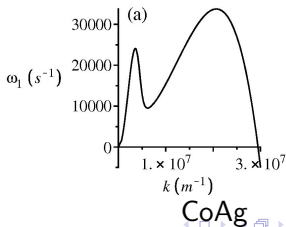
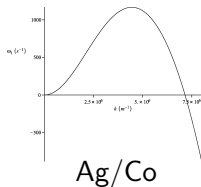
$$\partial_x \sigma_2 = -\gamma_2 \left((\partial_{h_1} T_2)|_{z=h_2} \partial_x h_1 + (\partial_{h_2} T_2)|_{z=h_2} \partial_x h_2 \right)$$

Dispersion relation:

$$\omega(k)^2 - (a_{11} + a_{22})\omega(k) + a_{11}a_{22} - a_{12}a_{21} = 0$$

- Coefficients a_{ij} are functions of the wavenumber k , initial thicknesses h_{10} , h_{20} , Hamaker coefficients and other parameters
- Roots ω_1 and ω_2 are real and distinct
- $|\omega_2(k)| \ll |\omega_1(k)|$

→ Only such perturbations destabilize the interfaces that have $\omega_1 > 0$ on some interval of the wavenumber k



Comparison of LSA and the experiment

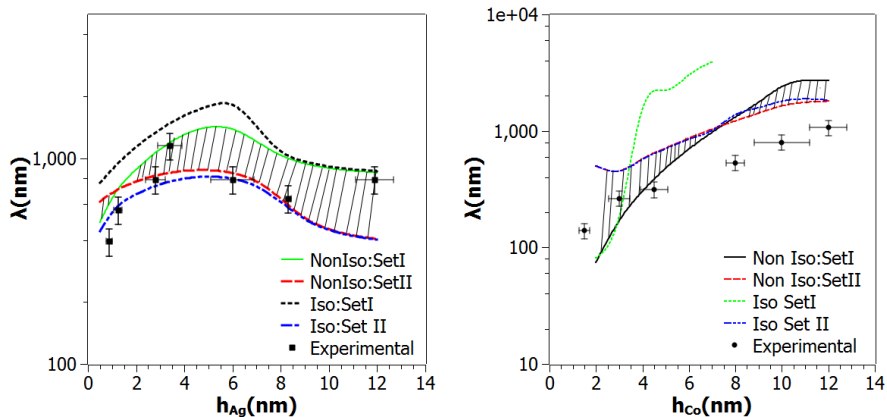
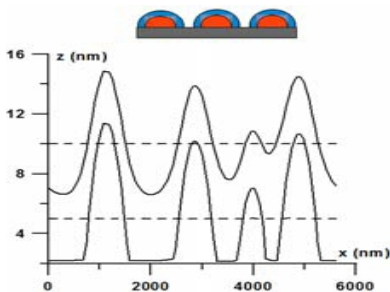


Figure: Particle spacing vs. the thickness of the top layer, for Ag/Co/SiO₂/Si and Co/Ag/SiO₂/Si systems with the bottom layer thickness fixed at 5 nm.

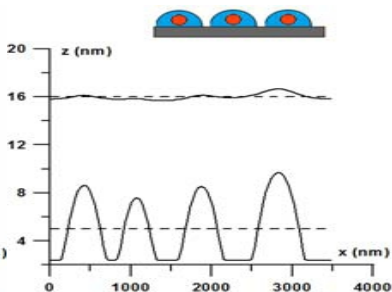
Simulation of the full nonlinear PDE system for Ag/Co bilayer

Co thickness = 5 nm fixed

Bilayer evolves in bending mode \rightarrow Formation of core-shell or embedded particles



Core-shell particles
Ag thickness = 5 nm

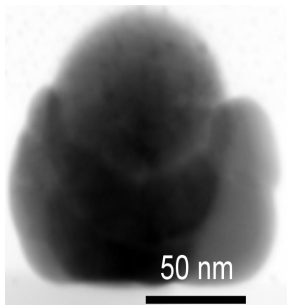
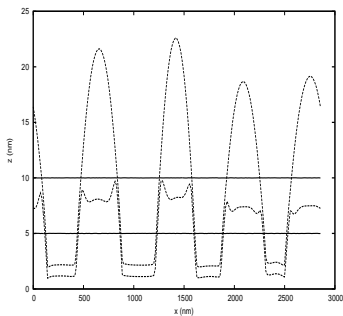


Embedded particles
Ag thickness = 11 nm

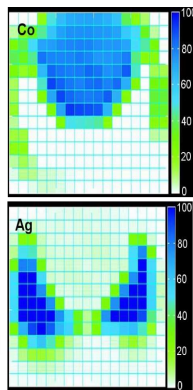
Simulation of the full nonlinear PDE system for Co/Ag bilayer

Bilayer evolves either in bending, or squeezing, or mixed bending/squeezing mode, depending on parameters (especially the Hamaker coefficients)

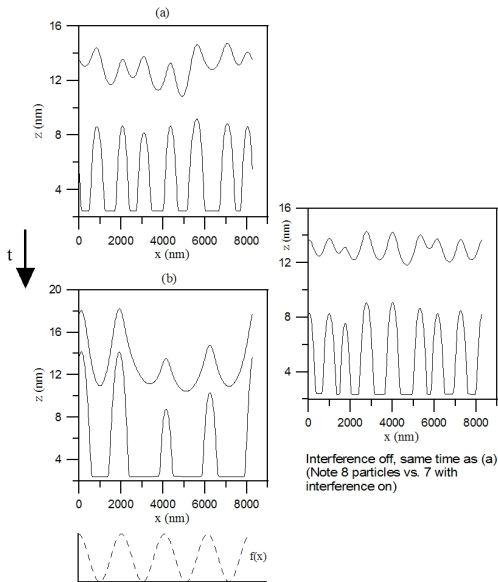
→ Formation of core-shell, embedded, or stacked particles



Stacked particles



Effect of interference heating on bilayer evolution



Single-layer films:

- 1 H. Krishna, R. Sachan, J. Strader, C. Favazza, M. Khenner, and R. Kalyanaraman, *Nanotechnology* 21, 155601 (2010) (experiment & theory)

Bilayer films:

- 1 H. Krishna, N. Shirato, S. Yadavali, R. Sachan, J. Strader, and R. Kalyanaraman, *ACS Nano* 5, 470-476 (2011) (experiment)
- 2 M. Khenner, S. Yadavali, and R. Kalyanaraman, "Formation of organized nanostructures from unstable bilayers of thin metallic liquids" (submitted, theory)
- 3 M. Khenner and R. Kalyanaraman, "Controlling Nanoparticles Formation in Molten Metallic Bilayers by Pulsed-Laser Interference Heating" (submitted, theory)